Notice of References Cited Application/Control No. 10/666,953 Applicant(s)/Patent Under Reexamination SUN ET AL. Examiner VAIBHAV (MANU) SAWHNEY 2616 Applicant(s)/Patent Under Reexamination SUN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0165185	09-2003	Arima et al.	375/147
*	В	US-6,707,856	03-2004	Gardner et al.	375/260
*	С	US-2004/0062215	04-2004	Sato, Takaharu	370/320
*	D	US-2003/0112743	06-2003	You et al.	370/203
*	E	US-2004/0004935	01-2004	Zhu et al.	370/208
*	F	US-2004/0047410	03-2004	Choi et al.	375/232
*	G	US-6,674,817	01-2004	Dolle et al.	375/342
*	Н	US-6,515,978	02-2003	Buehrer et al.	370/342
*	_	US-6,930,989	08-2005	Jones IV et al.	370/335
*	J	US-5,214,687	05-1993	Kansakoski et al.	455/425
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1193934	04-2002	EUROPEAN	Seo, Jae-Hyun et al.	H04L 27/26
	0					
	Р					
	Q					
	R					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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